



2 Description





SN74HC244-Q1 SCLS543C - SEPTEMBER 2002 - REVISED JUNE 2022

# SN74HC244-Q1 Octal Buffer and Line Driver With 3-State Outputs

#### 1 Features

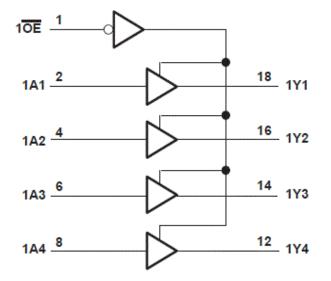
- Qualified for automotive applications
- ESD protection exceeds 2000 V per MIL-STD-883, Method 3015; exceeds 200 V using machine model (C = 200 pF, R = 0)
- Wide operating voltage range of 2 V to 6 V
- High-current outputs drive up to 15 LSTTL loads
- 3-state outputs drive bus lines or buffer memory address registers
- Low power consumption, 80-µA max I<sub>CC</sub>
- Typical  $t_{pd} = 11 \text{ ns}$
- ±6-mA output drive at 5 V
- Low input current of 1 µA max

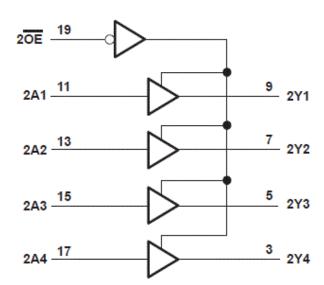
## This octal buffer and line driver is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The SN74HC244 is organized as two 4-bit buffers/ drivers with separate output-enable (OE) inputs. When $\overline{OE}$ is low, the device passes noninverted data from the A inputs to the Y outputs. When $\overline{OE}$ is high, the outputs are in the high-impedance state.

#### **Device Information**

PART NUMBER	PACKAGE <sup>(1)</sup>	BODY SIZE (NOM)		
SN74HC244QDW-Q1	SOIC (20)	12.80 mm × 7.50 mm		
SN74HC244QPW-Q1	TSSOP (20)	6.50 mm × 4.40 mm		

For all available packages, see the orderable addendum at the end of the data sheet.





**Functional Block Diagram** 



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<b>3 Revision History</b> NOTE: Page numbers for previous revisions may differ for	rom page numbers in the current version.
Changes from Revision B (February 2022) to Revisio	n C (June 2022) Page
Junction-to-ambient thermal resistance values increase.	sed. DW was 58 is now 109.1, PW was 83 is now 131.8
Changes from Revision A (April 2008) to Revision B	(February 2022) Page



# **4 Pin Configuration and Functions**

			1
10E	<sup>1</sup> O	20	□□ V <sub>cc</sub>
1A1 🗀	2	19	2 <u>0E</u>
2Y4 🗀	3	18	1Y1
1A2 🗀	4	17	2A4
2Y3 🗀	5	16	1Y2
1A3 🗀	6	15	2A3
2Y2	7	14	1Y3
1A4	8	13	2A2
2Y1 🗀	9	12	1Y4
GND 🗀	10	11	□□ 2A1
			ı

DW or PW Package 20-Pin SOIC or TSSOP Top View



## **5 Specifications**

## **5.1 Absolute Maximum Ratings**

over operating free-air temperature range<sup>(1)</sup>

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range		-0.5	7	V
I <sub>IK</sub>	Input clamp current <sup>(2)</sup>	$V_I < 0 \text{ or } V_I > V_{CC}$		±20	mA
I <sub>OK</sub>	Output clamp current <sup>(2)</sup>	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	$V_O = 0$ to $V_{CC}$		±35	mA
	Continuous current through V <sub>CC</sub> or GN	ID .		±70	mA
TJ	Junction temperature			150	°C
T <sub>stg</sub>	Storage temperature range		<b>–</b> 65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## 5.2 Recommended Operating Conditions<sup>(1)</sup>

			MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage		2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			V
		V <sub>CC</sub> = 6 V	4.2			
		V <sub>CC</sub> = 2 V			0.5	
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 4.5 V			1.35	V
	High-level input voltage			1.8		
VI	Input voltage		0		V <sub>CC</sub>	V
Vo	Output voltage		0		V <sub>CC</sub>	V
		V <sub>CC</sub> = 2 V			1000	
t <sub>t</sub>	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V			500	ns
		V <sub>CC</sub> = 6 V			400	
T <sub>A</sub>	Operating free-air temperature	<u>'</u>	-40		125	°C

<sup>(1)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

#### 5.3 Thermal Information

		DW (SOIC)	PW (TSSOP)	
THERMAL ME	ETRIC	20 PINS	20 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance <sup>(1)</sup>	109.1	131.8	°C/W
R <sub>θJC(top)</sub>	Junction-to-case (top) thermal resistance	76	72.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	77.6	82.8	°C/W
ΨЈТ	Junction-to-top characterization parameter	51.5	21.5	°C/W
ΨЈВ	Junction-to-board characterization parameter	77.1	82.4	°C/W
R <sub>θJC(bot)</sub>	Junction-to-case (bottom) thermal resistance	N/A	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

Product Folder Links: SN74HC244-Q1

<sup>2)</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



#### **5.4 Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V	T,	T <sub>A</sub> = 25°C		MIN MA	K UNIT	
PARAMETER	1231 0	ONDITIONS	V <sub>cc</sub>	MIN	TYP	MAX	WIN WA	CIVIT	
			2 V	1.9	1.998		1.9		
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		
V <sub>OH</sub>	$V_I = V_{IH}$ or $V_{IL}$		6 V	5.9	5.999		5.9	V	
		I <sub>OH</sub> = −6 mA	4.5 V	3.98	4.3		3.7		
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		
	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>			2 V		0.002	0.1	0.	1
			I <sub>OL</sub> = 20 μA	4.5 V		0.001	0.1	0.	1
V <sub>OL</sub>			6 V		0.001	0.1	0	1 V	
		I <sub>OL</sub> = 6 mA	4.5 V		0.17	0.26	0	4	
		I <sub>OL</sub> = 7.8 mA	6 V		0.15	0.26	0	4	
I <sub>I</sub>	$V_I = V_{CC}$ or 0		6 V		±0.1	±100	±100	0 nA	
I <sub>OZ</sub>	$V_O = V_{CC}$ or 0,	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	6 V		±0.01	±0.5	±1	0 μΑ	
I <sub>CC</sub>	$V_I = V_{CC}$ or 0,	I <sub>O</sub> = 0	6 V			8	16	0 μΑ	
C <sub>i</sub>			2 V to 6 V		3	10	1	0 pF	

## **5.5 Switching Characteristics**

over recommended operating free-air temperature range,  $C_L$  = 50 pF (unless otherwise noted) See: (Parameter Measurement Information)

PARAMETER	FROM			T,	<sub>A</sub> = 25°C		MIN	MAY	UNIT
PARAWETER	(INPUT)	(OUTPUT)	V <sub>CC</sub>	MIN	TYP	MAX	IVIIIN	MAX	UNII
			2 V		40	115		170	
t <sub>pd</sub>	Α	Y	4.5 V		13	23		34	ns
			6 V		11	20		29	
			2 V		75	150		225	
t <sub>en</sub>	ŌĒ	Y	4.5 V		15	30		45	ns
			6 V		13	26		38	
			2 V		75	150		225	
t <sub>dis</sub>	ŌĒ	Y	4.5 V		15	30		45	ns
			6 V		13	26		38	
t <sub>t</sub>			2 V		28	60		90	
		Y	4.5 V		8	12		18	ns
			6 V		6	10		15	

# **5.6 Operating Characteristics**

T<sub>A</sub> = 25°C

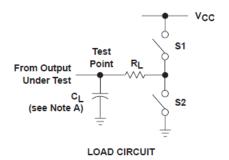
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per buffer/driver	No load	35	pF

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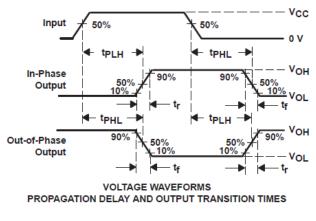
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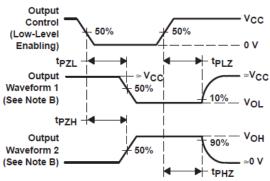


#### **6 Parameter Measurement Information**



PARAI	METER	RL	CL	<b>S</b> 1	S2
	ten ten 1 kΩ 50 pF		Open	Closed	
ten	t <sub>PZL</sub>	1 K22	50 pr	Closed	Open
t.e.	t <sub>PHZ</sub>	1 kΩ	50 pF	Open	Closed
<sup>t</sup> dis	tPLZ	1 1132	30 pi	Closed	Open
t <sub>pd</sub> or	t <sub>t</sub>	1	50 pF	Open	Open





Input 50% 50% 0 V

10% 10% 0 V

VOLTAGE WAVEFORM
INPUT RISE AND FALL TIMES

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- A.  $C_L$  includes probe and test-fixture capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_f = 6$  ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

Figure 6-1. Load Circuit and Voltage Waveforms

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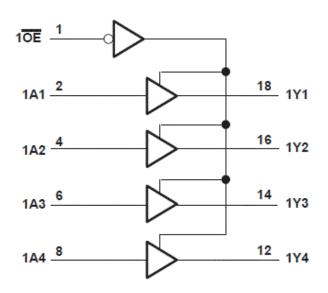
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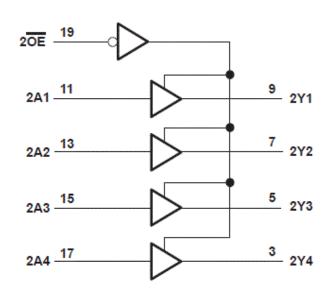
## 7 Detailed Description

### 7.1 Overview

This octal buffer and line driver is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The SN74HC244 is organized as two 4-bit buffers/drivers with separate output-enable  $(\overline{OE})$  inputs. When  $\overline{OE}$  is low, the device passes noninverted data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

### 7.2 Functional Block Diagram





#### 7.3 Device Functional Modes

Table 7-1. Function Table (each buffer/driver)

INP	OUTPUT	
ŌĒ	Α	Y
L	Н	Н
L	L	L
Н	Х	Z

## 8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V<sub>CC</sub> terminal should have a good bypass capacitor to prevent power disturbance. A 0.1-µF capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1-µF and 1-µF capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

## 9 Layout

#### 9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.

## 10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

### 10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 10.2 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

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#### 10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

## 10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

## 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
SN74HC244QDWRQ1	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q
SN74HC244QDWRQ1.A	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q
SN74HC244QPWRG4Q1	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q
SN74HC244QPWRG4Q1.A	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q
SN74HC244QPWRQ1	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q
SN74HC244QPWRQ1.A	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q
SN74HC244QPWRQ1.B	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	-	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



# **PACKAGE OPTION ADDENDUM**

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#### OTHER QUALIFIED VERSIONS OF SN74HC244-Q1:

● Enhanced Product : SN74HC244-EP

• Military : SN54HC244

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

• Military - QML certified for Military and Defense Applications

# **PACKAGE MATERIALS INFORMATION**

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### TAPE AND REEL INFORMATION





	-
A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

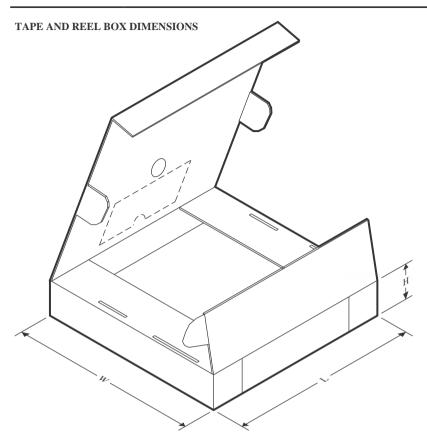
#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HC244QDWRQ1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN74HC244QPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74HC244QPWRQ1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1

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### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HC244QDWRQ1	SOIC	DW	20	2000	356.0	356.0	45.0
SN74HC244QPWRG4Q1	TSSOP	PW	20	2000	353.0	353.0	32.0
SN74HC244QPWRQ1	TSSOP	PW	20	2000	353.0	353.0	32.0



SMALL OUTLINE PACKAGE



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SOIC



#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

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  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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